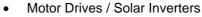


1200V thinQ![™] SiC Schottky Diode

Features:

- Revolutionary Semiconductor Material -Silicon Carbide
- Switching Behaviour Benchmark
- No Reverse Recovery / No Forward Recovery
- Temperature Independent Switching Behaviour
- Qualified According to JEDEC¹⁾ Based on Target Applications

Applications:











Chip Type	V_{R}	<i>I</i> Fn	Die Size	Package		
IDC08S120E	1200V	7.5A	2.012 x 2.012 mm ²	sawn on foil		
Mechanical Paramete	ers					
Die size			2.01	2.012 x 2.012		
Area total				mm ²		

Die size		2.012 x 2.012		
Area total		4.05	mm ²	
Anode pad size		1.476 x 1.476		
Thickness		362	μm	
Wafer size		100	mm	
Max. possible chips per	wafer	1652		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500μm		
Reject ink dot size		Ø 0.65mm; max 1.2mm		
Storage environment ¹⁾	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month		
	for open MBB bags	Acc. to IEC60721-3-3: Atmosphere >99% Nitroger gas, Humidity <25%RH, Temperature 17°C – 25°C,		

¹⁾ Designed for storage conditions according to Infineon TR14 (Application Note "Storage of Products Supplied by Infineon Technologies)

Designed for climate condition under operation according to IEC60721-3-3, class 3K3

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Maximum Ratings

Parameter	Symbol	Condition	Value	Unit	
Repetitive peak reverse voltage	V_{RRM}	<i>T</i> _{vj} =25 °C	1200	V	
DC blocking voltage	V _{DC}		1200	V	
Continuous forward current, limited by T_{vjmax}	I _F	T _{vj} < 150°C	7.5		
Surge non repetitive forward current,	,	$T_{\rm C} = 25^{\circ} {\rm C}$, $t_{\rm P} = 10 {\rm ms}$	39		
sine halfwave	I _{F,SM}	$T_{\rm C} = 150^{\circ} {\rm C}_{ f_{\rm P}} = 10 {\rm ms}$	33	A	
Repetitive peak forward current, limited by thermal resistance R_{th}	I _{F,RM}	$T_{\rm C} = 100^{\circ} {\rm C}, \ T_{\rm vj} = 150^{\circ} {\rm C},$ D = 0.1	32		
Non-repetitive peak forward current	I _{F,max}	$T_{\rm C} = 25^{\circ}{\rm C}, \ t_{\rm P} = 10 \mu{\rm s}$	160		
i ² t value	$\int i^2 dt$	$T_{\rm C}$ =25°C, $t_{\rm P}$ =10 ms	7	– A ² s	
i t value	J' at	$T_{\rm C} = 150^{\circ} {\rm C}_{ f} t_{\rm P} = 10 {\rm ms}$	5	- AS	
Operating junction and storage temperature range	$T_{\rm vj}$, $T_{\rm stg}$		-55+175	°C	

Static Characteristics (tested on wafer), T_{v_j} = 25 °C

Parameter	Symbol Conditions	Conditions		Unit		
		Conditions	min.	Тур.	max.	Onit
Reverse current	I_{R}	V _R =1200V		8	180	μΑ
Diode forward voltage	V _F	I _F =7.5A		1.6	1.8	V

Static Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions		Unit		
raidillelei	Symbol	Conditions	min.	Тур.	max.	Oilit
Reverse current	I_{R}	$V_{R} = 1200 \text{ V}, T_{vj} = 150 ^{\circ}\text{C}$		30	1000	μA
Diode forward voltage	V _F	I _F =7.5A, T _{vj} =150°C		2.5	3	V



Dynamic Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Canditi	Conditions		Value		
rarameter	Symbol	Conditions		min.	Тур.	max.	Unit
Total capacitive charge ³⁾	Q _C	$I_F <= I_{F,max}$	T _{vj} =150°C		27		nC
Switching time ²⁾	t _c	$di/dt = 200 A/\mu s$ $V_R = 1200 V$	T _{vj} =150°C			<10	ns
			V _R =1 V		380		
Total capacitance	С	f=1MHz	V _R =300V		30		pF
			V _R =600V		27		

Further Electrical Characteristics

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

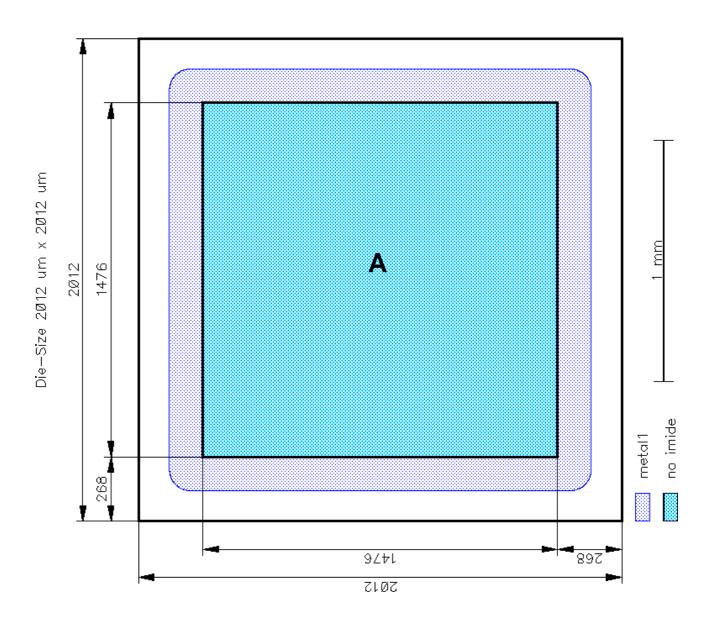
This chip data sheet refers to the device data sheet IDH08S120 Rev. 1.0	This chip data sheet refers to the device data sheet	IDH08S120	Rev. 1.0
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¹⁾ J-STD20 and JESD22
²⁾ $t_{\rm c}$ is the time constant for the capacitive displacement current waveform (independent from $T_{\rm vj}$ =150°C, $I_{\rm LOAD}$ and dl/dt), different from $t_{\rm rr}$, which is dependent on $T_{\rm vj}$ =150°C, $I_{\rm LOAD}$, dl/dt. No reverse recovery time constant $t_{\rm rr}$ due to absence of minority carrier inject.
³⁾ Only capacitive charge occurring, guaranteed by design (independent from $T_{\rm vj}$, $I_{\rm LOAD}$ and dl/dt).





Chip Drawing



A: Anode pad

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Date

Description	
AQL 0,65 for visual inspection according to failure catalogue	
Electrostatic Discharge Sensitive Device according to MIL-STD 883	
Revision History	_

Subjects (major changes since last revision)

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Version

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